

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/706,406	TAGG, JAMES P.	
Examiner Hai V. Nguyen		Art Unit 2142	Page 1 of 1	

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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